

EL 355818248

Inventor: Klaus Florian Schuegraf et al.  
Title: Methods For Forming Wordlines, Transistor Gates, And Conductive  
Interconnects, And Wordline, Transistor Gate, and Conductive  
Interconnect Structures  
Assignee: Micron Technology, Inc.

10525 U.S. PTO  
09/332271  
06/11/99

#9  
2/5/01  
M. Bridges

**INFORMATION DISCLOSURE STATEMENT**

The Examiner's attention is directed to the references listed on the attached  
Form PTO-1449 and copies of which are attached.  
Citation of these references are respectfully requested.

Respectfully submitted,

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David G. Latwesen, Ph.D.  
Reg. No. 38,533

Date: 6/11/99

Inventor: Klaus Florian Schuegraf

Date: \_\_\_\_\_

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Date: 5/24/99

Inventor: Randhir P. S. Thakur  
Randhir P. S. Thakur

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-532	SERIAL NO. Unknown		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Klaus Florian Schuegraf et al.			
				FILING DATE Filed herewith	GROUP Unknown		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,425,392	06/95	Thakur et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK		Taishi Kubota et al.; "The Effect of the Floating Gate/Tunnel SiO <sub>2</sub> Interface on FLASH Memory Data Retention Reliability"; 1994; 2 pages				
	AL		Shoue Jen Wang et al.; "Effects of Poly Depletion on the Estimate of Thin Dielectric Lifetime"; IEEE Electron Device Letters, Vol. 12, No. 11, November 1991; pp. 617-619				
	AM		Klaus F. Schuegraf et al.; "Impact of Polysilicon Depletion in Thin Oxide MOS Technology"; 1993; pp. 86-88				
	AN		E. H. Snow et al.; "Polarization Phenomena and Other Properties of Phosphosilicate Glass Films on Silicon"; Journal of the Electrochemical Society, March 1966; pp. 263-269				
EXAMINER				DATE CONSIDERED			
<p><small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small></p>							